

# Atomic Force Microscopy

## a) Scan Parameters

Scan the calibration grid with the following parameters:

Scan size:  $50\ \mu\text{m} \times 50\ \mu\text{m}$

$P = 100$ ,  $I = 10$ , scan speed = 3Hz

Acquire both forward and backward scans.

What happens by changing the values of  $P$  and  $I$ ?

(reasonable  $P, I$  values can be between 1 and 250)

Which are optimal settings in this particular case?

Comment and analyze the results by comparing images and line profiles.

## b) Scan Speed

Scan the calibration grid with the following parameters:

Scan size:  $50\ \mu\text{m} \times 50\ \mu\text{m}$

$P = 100$ ,  $I = 10$

What happens by increasing / decreasing the scan speed in between a few Hz and way below 1Hz?

Comment and analyze the results by comparing images and line profiles for the three different scan speeds.

## c) Analysis

Acquire a picture with optimized parameters for  $P$ ,  $I$  and scan speed. Determine periodicity, lateral and vertical dimensions of the features present on the sample. Do a proper consideration of measurement and statistical errors.

## d) Digital Optical Media

After optimizing the scan parameters for each sample, take AFM images for two of the following media: CD, DVD, BluRay Disc. Measure the track spacing and channel bit length. Use both: pits and lands and comment on their difference in AFM images. Compare with literature values. Estimate the data capacity that can be stored on the different media. Do a proper consideration of measurement and statistical errors.

## e) Quantum Dots

After optimizing the scan parameters, take a high-resolution image of the quantum dot sample. Plot a statistic on the size of the quantum dots and comment the obtained results. Also compare with respect to the used AFM tip with radius  $r_{\text{tip}} < 8\ \text{nm}$ . Do a proper consideration of measurement and statistical errors.